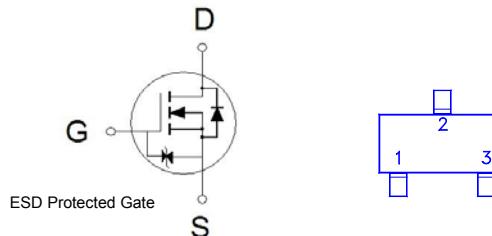


**NIKO-SEM**
**N-Channel Logic Level Enhancement  
Mode Field Effect Transistor  
(Preliminary)**
**PZD502CY**  
**SOT-323**  
**Halogen-Free & Lead-Free**
**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
20V	450mΩ	0.75A


1. GATE  
2. DRAIN  
3. SOURCE
**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		$V_{DS}$	20	V
Gate-Source Voltage		$V_{GS}$	$\pm 8$	V
Continuous Drain Current	$T_A = 25^\circ\text{C}$	$I_D$	0.75	A
	$T_A = 70^\circ\text{C}$		0.6	
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	2	
Power Dissipation	$T_A = 25^\circ\text{C}$	$P_D$	0.49	W
	$T_A = 70^\circ\text{C}$		0.3	
Operating Junction & Storage Temperature Range		$T_j, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient <sup>2</sup>	$R_{\theta JA}$		255	°C/W

<sup>1</sup>Pulse width limited by maximum junction temperature.<sup>2</sup>The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.**ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	20			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	0.35	0.65	1	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 8V$			$\pm 30$	$\mu\text{A}$
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 16V, V_{GS} = 0V$			1	$\mu\text{A}$
		$V_{DS} = 10V, V_{GS} = 0V, T_J = 55^\circ\text{C}$			10	
Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(\text{ON})}$	$V_{GS} = 1.8V, I_D = 0.35\text{A}$		464	850	$\text{m}\Omega$
		$V_{GS} = 2.5V, I_D = 0.5\text{A}$		307	765	
		$V_{GS} = 4.5V, I_D = 0.6\text{A}$		240	450	
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 5V, I_D = 0.6\text{A}$		2		S

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DYNAMIC						
Input Capacitance	$C_{iss}$			38		
Output Capacitance	$C_{oss}$			16		pF
Reverse Transfer Capacitance	$C_{rss}$			12		
Total Gate Charge <sup>2</sup>	$Q_g$			1.4		
Gate-Source Charge <sup>2</sup>	$Q_{gs}$			0.4		nC
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$			0.8		
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$			6		
Rise Time <sup>2</sup>	$t_r$			18		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$			30		nS
Fall Time <sup>2</sup>	$t_f$			25		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ( $T_J = 25^\circ C$ )						
Continuous Current	$I_S$				0.75	A
Forward Voltage <sup>1</sup>	$V_{SD}$				1.2	V
Reverse Recovery Time	$t_{rr}$				233	
Reverse Recovery Charge	$Q_{rr}$				630	nC

<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .

<sup>2</sup>Independent of operating temperature.